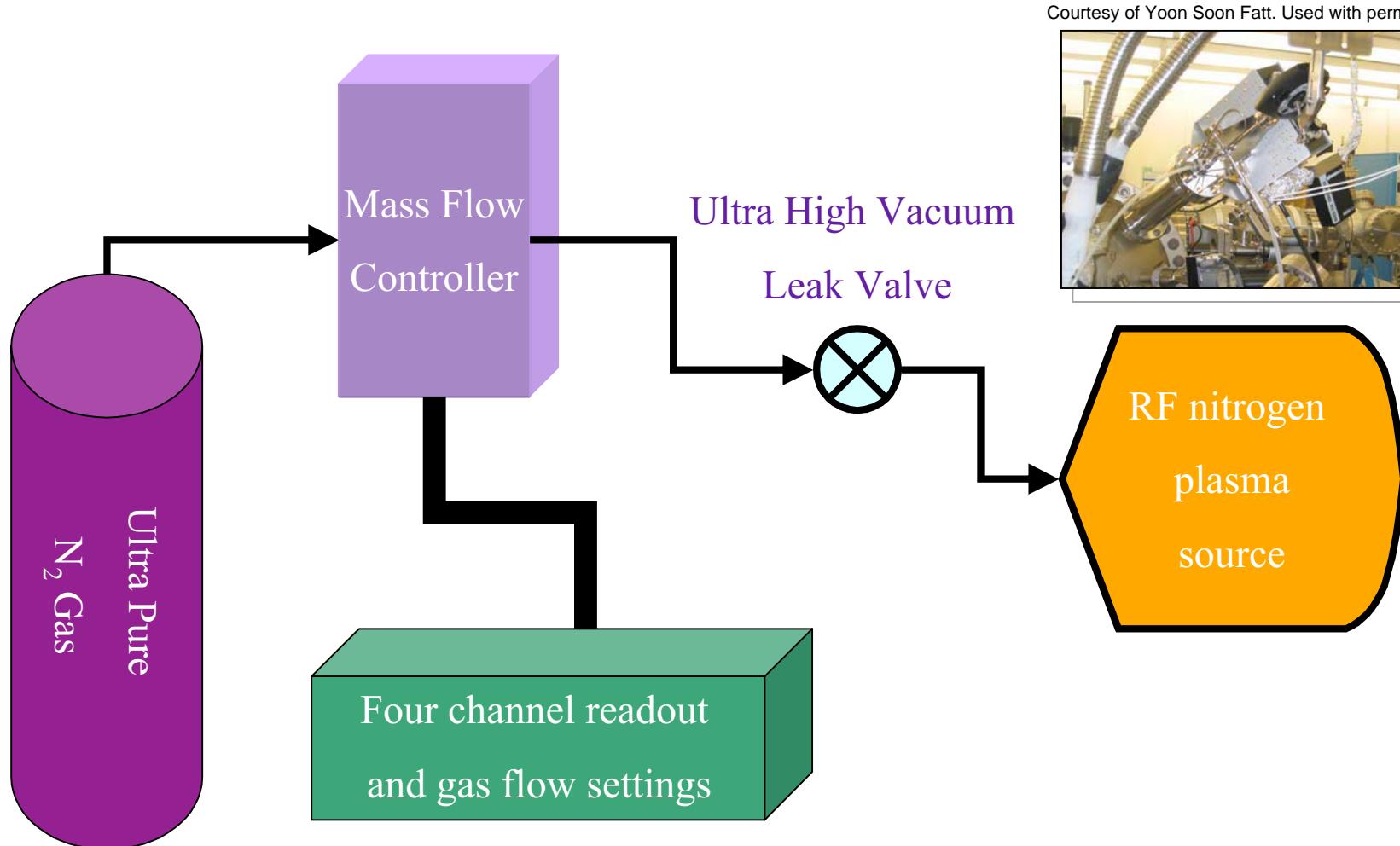
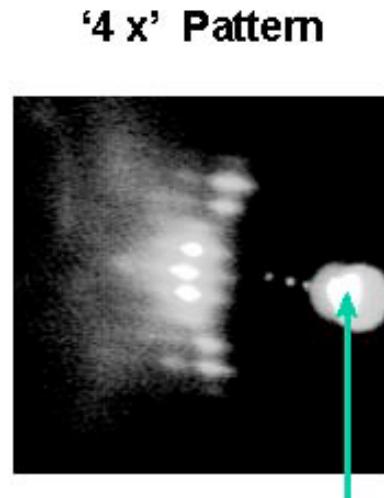
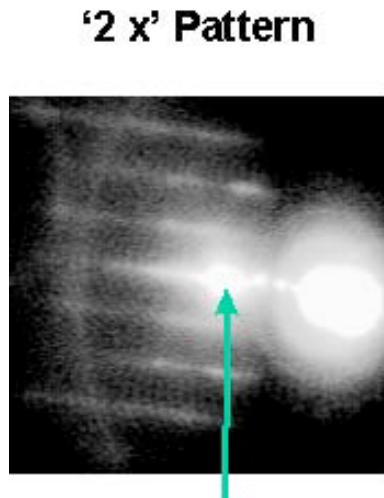


# Control of r. f. nitrogen plasma source in solid source MBE



Courtesy of Professor Yoon Soon Fatt, NTU.

# *In-situ* monitoring of monolayer growth □



Courtesy of Professor Yoon Soon Fatt, NTU.

Courtesy of Professor Yoon Soon Fatt, NTU.

Reflection high energy electron  
diffraction (RHEED) pattern of a GaAs  
surface observed during epitaxial growth  
at As overpressure condition.



Courtesy of Yoon Soon Fatt, NTU.

## **Insert 1 - MBE surface reconstruction and RHEED □**

### **MBE surface action**

- 1. Growth mechanism**
- 2. Surface reconstruction**
- 3. RHEED system overview**
- 4. Origins of RHEED oscillations**
- 5. Control panel w. RHEED display**
- 6. RHEED oscillation plot**

# Variations on the MBE theme □

## Solid Source MBE - all elemental sources □

Advantages: no toxic gases

Disadvantages: large heat load; phosphides require cracker or sublimation source

## Gas Source MBE - column V hydrides; elemental group III's □

Advantages: easy access to phosphides; no As or P cells to recharge □

Disadvantages: large heat load; toxic gases; additional pump load □

## Metalorganic MBE - column III metalorganics; elemental V's □

Advantages: reduced heat load

Disadvantages: phosphides difficult; MO purity an issue; carbon contamination a concern; additional pumping load; little advantage over SSMBE; more complex chemistry

## Chemical Beam Epitaxy - MOCVC in high vacuum, beam limit □

Advantages: small heat load; phosphides easy; selective area growth possible

Disadvantages: additional pumping load; carbon contamination possible; MO purity an issue; toxic gases

# Critiquing the Epitaxy Techniques □

## Liquid Phase Epitaxy □

Advantages: inexpensive; equilibrium growth; excellent layer quality; low toxicity

Disadvantages: complicated to do multiple layers; poor thickness control; materials and combinations limited; uniformity an issue; hard to scale up

## Vapor Phase Epitaxy [chloride and hydride transport] □

Advantages: high purity; low toxicity

Disadvantages: complex, messy; memory effects; poor thickness control; uniformity an issue

## Metalorganic Chemical Vapor Deposition [esp. low P] □

Advantages: excellent control; fast response; versatile; many materials; selective area growth possible □

Disadvantages: toxic gases; uniformity an issue □

## Molecular beam epitaxy □

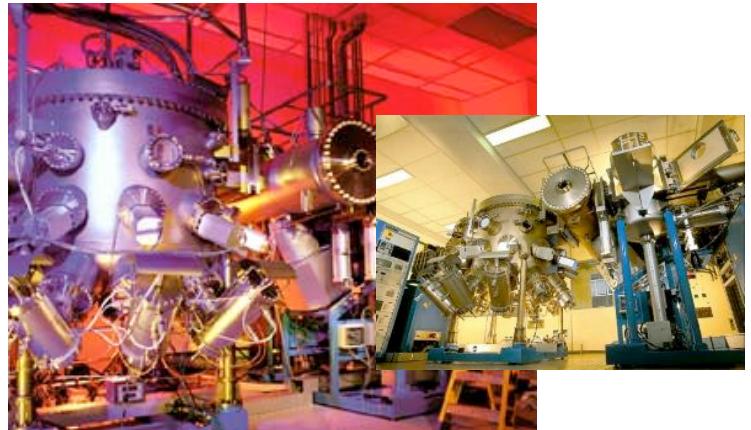
Advantages: beam technique; insitu monitoring; monolayer control

Disadvantages: slow; expensive; maintenance of UHV required

# Epitaxial growth techniques □

## ■ Molecular Beam Epitaxy (MBE)

- Ultra high vacuum condition
    - □ Solid source MBE – Elemental □ sources of In, Ga, Al, As and P □
    - □ Gas source MBE – Combination of □ elemental source (for group III) and □ gas source (for group V)



Riber Production MBE6000  
(Courtesy of MBE Technology  
(S) Pte Ltd)

## ■ Metalorganic Chemical Vapor Deposition (MOCVD)

- Low vacuum condition 
    - Gas sources such as TMG, TMI, TMA, AsH<sub>3</sub>, and PH<sub>3</sub>, are used.



## **Insert 2 - Comparison of MOCVD and MBE results** □

### **Comparison of MOCVD and MBE**

- 1. RTD performance**
- 2. 2DEG mobility**
- 3. PL spectra of AlGaAs**

# Growing Quantum Wires and Dots - beyond quantum wells

## Grow and pattern

- Growing quantum wells and patterning them into wires and/or dots is generally not the method used. The patterns needed are too small and the dimensions are hard to control.

## Direct growth

- The more common approach is to grow on a specially prepared surface so that the resulting heterostructure contains quantum wires or dots
- Quantum wires:
  - 1. Growth on stepped surfaces
  - 2. Growth on grooved surfaces
- Quantum dots:
  - Growth of thin, highly mismatched layers

# Growing Quantum Wires - □

## MOCVD on V-grooves

(Image deleted)

See M. Walther et al, Appl. Phys. Lett. 60 (1992) 521-3.

(Image deleted)

See X-L Wang et al, Appl. Phys. Lett. 71 (1997) 2130-2.

## TEM

### Growth objective

(Image deleted)

See M. Walther et al, Appl. Phys. Lett. 60 (1992) 521-3.

(Image deleted)

See X-L Wang et al, Appl. Phys. Lett. 71 (1997) 2130-2.

## TEM

### Calculated wavefunctions

## Growing Quantum Dots - dots = boxes □

### Stranski Krastanov strain-driven growth of dots: □

#### Layer sequence □

(Images deleted)

See M. H. Son et al, Appl. Phys. Lett. 82 (2003) 1230-3.

#### Cross-section TEM of stacked dots (termed self-assembled quantum dots, SAQDs)

After somewhat more than a monolayer of InAs has been deposited, dots form. Empirically it is found that 1.8 monolayers per dot layer is an "optimum" amount.

The dots in subsequent layers tend to form over the underlying dots, resulting in ordered stacking (self-assembly).

## **III-V Processing - General Comments/Overview**

### General Picture

**III-V device processing is in general more complex than silicon processing in that**

- 1. there are no native oxides comparable to  $\text{SiO}_2$**
- 2. many of the constituent elements in the III-V semiconductors have high vapor pressures and are subject to decomposition unless encapsulated or under pressure**

**On the other hand, with the III-Vs**

- 1. one has the availability of complex heterostructures**
- 2. there are very selective etches available to differentiate between heterostructure components**

## **III-V Processing - General Comments, cont. □**

### Doping □

**diffusion:** open tube (a la Si) not practical  
sealed ampoule - to provide As or P overpres.  
from spin-on glasses and doped metals

**ion implantation:** standard process  
RTA activation

### Device isolation

mesa etching

**proton ( $H^+$ ) bombardment:** makes many wider bandgap  
III-V's like GaAs, InP high resistance

### Passivation, encapsulation □

**no native oxides; oxidation not viable - sulfidation**  
maybe

**deposited  $SiO_2$  and  $Si_3N_4$  widely used - Ga diffuses thru  
 $SiO_2$ , but not  $Si_3N_4$**

## III-V Processing - General Comments, cont. □

### Ohmic contacts

deposition and alloy of doped metals - e.g. Au-Zn  
narrow bandgap ohmic contact layer - e.g. InGaAs  
heavily doped layer contact layer - Si standard too.

### Wet etching

there are highly selective etches for III-V hetero-structures that can be used to advantage in device processing:

Etchants that differentiate between AlGaAs and AlAs, or between GaAs and AlGaAs for selected AlGaAs aluminum fraction ranges

Similar etchants in the InGaAlAs system

Etchants that differentiate between InGaAlAs and InP

### Dry etching

widely employed: see following foils

## Insert 3 - III-V processing □

Etching, doping, and contacting the III-Vs □  
(22 foils from Prof. Chua Soo Jin, NUS) □

Final comments - What's hot in epi today... □

AlGaInN on whatever: substrates are the problem  
Sapphire ( $\text{Al}_2\text{O}_3$ ), Silicon Carbide (SiC)  
Gallium Nitride - if available  
Si - <111> best

InGaAs on GaAs and GaInAsN on GaAs: getting  
longer wavelength, higher mobilities on an inexpensive  
substrate (rather than on InP)

GaAs and InP on Si: dealing with 1. lattice mismatch, □  
2. antiphase domains, and 3. thermal expansion coefficients